

Sheet 1 of 1

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>15146-011001</b>	Application No. <b>10/758,277</b>
	Applicant <b>Genichi Imamura</b>		
	Filing Date <b>January 16, 2004</b>	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
BY	AA	5,519,440	05/21/1996	BAKER			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
BY	AO	SDTV/HDTV, <a href="http://www.tektronix.co.jp/Products/M Measurement Prod/App notes/wfm700 gamut measure.pdf">http://www.tektronix.co.jp/Products/M Measurement Prod/App notes/wfm700 gamut measure.pdf</a> , 4 pages (Abstract only translated)
BY	AP	"Multi-format, Multi-standard Waveform Monitors," <a href="http://www.tek.com/site/ps/1,25-14575-INTRO_EN,00.html?wt=340&amp;link=/site/ps/1,25-14575-INTRO_EN,00.html">http://www.tek.com/site/ps/1,25-14575-INTRO_EN,00.html?wt=340&amp;link=/site/ps/1,25-14575-INTRO_EN,00.html</a> , 17 November 2003, 24 pages.
	AQ	
	AR	

Examiner Signature <b>/Brian Yenke/</b>	Date Considered <b>07/13/2006</b>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Disclosure Form (PTO-1449)